A/D/A/M-822

Simultaneously Sampling
Low Cost

12-bit Analog-to-Digital Converter

DESCRIPTION

The A/D/A/M-822 is a self-contained, two-channel, analog-to-digital conversion module complete with two simultaneously operating sample-and-hold (S/H amplifiers, a stable reference, and a 12-bit successive approximation A/D converter. An added feature is the fact that this unit includes four input channels that can be chosen in two groups of two each. This module has been designed to simplify the hardware and software of systems that utilize two or more phase- or time-related signal channels or cross-channel measurements such as quadrature demodulated signal processor front-ends, component transfer function testers, and colorimeters. By adding a multiplexer to each of the four inputs of the A/D/A/M-822, a mini-DAS (Data Acquisition System) can be configured at a very modest cost.

In many systems, information of interest is often carried by the time-or phase-interrelationship among signal channels. Such information may be lost when time-shared S/H's are used or when dedicated S/H's are triggered with insufficient simultaneity. Sequential sampling of the related signals may require costly software correction of errors induced by the sampling process; such correction methods are generally useful only if the delay between samples is known precisely. The A/D/A/M-822 eliminates these sources of error and additional system cost by providing simultaneous sampling of either channel pair—within 5ns of each other. For an equivalent system configuration, only half of the number of A/D converters need be used, further reducing overall system costs.

The specification for the A/D/A/M-822 is based on an end-to-end error budget that accounts for all internal error sources, including S/H droop at a 26 kHz sampling rate, error due to aperture uncertainty for band limited signals up to 12.5 kHz, S/H pedestal non-linearities, input switching crosstalk, and A/D non-linearities. With a throughput time for two digitized samples of less than 40 microseconds, it provides 12-bit (\pm 1 LSB) overall accuracy. The use of discrete component S/H amplifiers contributes greatly to the overall accuracy of the A/D/A/M-822—

(continued on page 3)

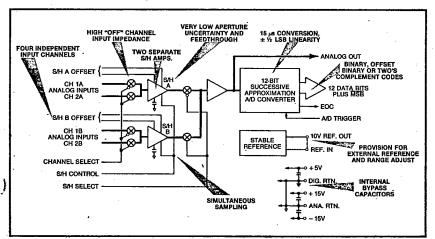


Figure 1. A/D/A/M-822 Functional Block Diagram. High precision sample & holds ensure low aperture uncertainty and high measurement accuracy.

FEATURES

- Guaranteed Overall Transfer
 Accuracy
 ± 0.025% FSR, maximum
- High Throughput Rate at Low Cost Two Channels at 26,000 samples per second each Single Channel at 52,600 samples per second
- Low Aperture Uncertainty
 Time—5 ns
 Minimizes phase error between
 simultaneously sampled
 channels
- Universal Data Systems
 Compatibility
 Standard TTL digital
 Inputs/outputs
- Low Power 1.25W, typ.
- Low Noise
 0.01% FSR
- Flexibility
 Independently selectable input
 channel pairs
 Multiple units can be driven by
 single TTL line driver for multiple
 simultaneously sampled
 channels
- Ratiometric Operation
- Superior Performance
 Lower cost and higher overall
 accuracy when compared to
 functionally equivalent designs
 based on integrated circuits.
- Small Size 2" X 3" X 0.375" (50.8 mm X 76.2 mm X 9.53 mm)
- RFI & EMI Shielded

ANALOGIC® Solutions...not Slogans

AND/A/M-822 SPECIFICATIONS

ANALOG INPUTS

Number of Channels 4 (2 pair) Configuration Voltage follower input Full Scale Range (FSR) 0 to + 10V, ±5V, ±10V (see Ordering Guide) Maximum Input Without Damage ± 15V Input Impedance >100 MΩ Input Bias Current' ≤1nA (at 25°C)

ACCURACY (at 26 kHz sampling rate and 25°C, nominal)

Relative Accuracy² **Differential Non-Linearity** ±30 Noise (Shorted Input; measured over do to 1 MHz Bandwidth) Monotonicity ±0.025% FSR max ± 1/2 LSB max.

0.01% FSR, p-p Referenced to Input, max. Guaranteed; No missing codes

S/H Hold Mode Feedthrough Rejection

Channel-to-Channel Crosstalk⁴ Offset Error (Untrimmed)5 Gain Error (Untrimmed)5.6 Gain Accuracy Between Channels 82 dB; 1 kHz square wave, full scale

- 110 dB @ 10 kHz 25 mV, max.; adjustable to zero

± 0.25% FSR max.

± 7.5 mV max.

DYNAMIC PERFORMANCE

Maximum Dual Channel Sampling Rate⁷ Maximum Single Channel Sampling Rate® S/H Acquisition Time to 1/2 LSB S/H Aperture Delay Time S/H Aperture Uncertainty Time 26 kHz (2 samples/39 microseconds) 52.6 kHz

5 µs max. 50 ns typ, 5 ns typ.

0.02 μ V/ μ s typ., 0.2 μ V/ μ s max. Refer to timing diagram (Figure 2) S/H Droop Rate (at 25°C) Input Switching and S/H Multiplexer Settling Time to ± 1/2 LSB

STABILITY

Tempco of Differential Non-Linearity Tempco of Offset — Unipolar Tempco of Offset — Bipolar Tempco of Gain **Power Supply Sensitivity**

Recommended Recalibration Interval

Warm-up Time to Specified Accuracy

± 3 ppm/°C FSR max.

± 10 ppm/°C, FSR max. ± 15 ppm/°C, FSR max. ± 20 ppm/°C, FSR max.

0.003% FSR/% change in Vsupply

6 months 5 minutes

DIGITAL INTERFACES

General

Inputs: 1 TTL LS load, each; Outputs: 2 TTL load fanout, each

TTL positive true is logic "1"

Logic "0": 0.4V max. for outputs; 0.8V max. for inputs Logic "1": 2.4V min. for outputs; 2.0V min. for inputs

Inputs

Input Channel Select

Logic "0" selects channel 1; logic "1" selects channel 2

S/H Select S/H (Mode) Control A/D Trigger Logic "0" selects S/H A; logic "1" selects S/H B Logic "0" selects HOLD mode; logic "1" selects SAMPLE

Positive pulse, trailing edge triggered; 0.1 µs pulse width minimum

Outputs

12 data bits in Binary, 2's Complement, or Offset Binary (see Data Coding Table for format)

EOC Logic "1" during conversion

POWER & ENVIRONMENTAL

Analog Power Requirements* Digital Power Requirement^e **Operating Temperature** Storage Temperature Relative Humidity ModupacTM Dimensions **Electromagnetic Shielding** Electrostatic Shielding

+ 15V ±3% @ 35 mA, typ. & - 15V @ 35 mA, typ.

+5V, $\pm 3\%$ 40 mA, typ. 0°C to 70°C

25°C to +85°C

Up to 95%, non-condensing 2" X 3" X 0.375" (50.8 mm X 76.2 mm X 9.53 mm)

5 sides 6 sides

NOTES:

- Doubles every 10°C.
- Includes effects of input switching, buffer amplifiers, S/H Amp and ADC.
- Measured on S/H output, in HOLD mode with input signal as stated. Measured on Channel A S/H output with input grounded. Input signal applied to Channel B input. Both channels in SAMPLE mode.
- Offset and gain errors are externally adjustable see Figures 3 and 4.
- With 50 Ω , 1% fixed resistor installed per Figure 4. On \pm 10V FSR.
- On ± 5V FSR; 50 kHz on ± 10V FSR.
- Digital Ground, Analog Ground, and case are tied internally.

DESCRIPTION

(continued from page 1)

by contrast functionally comparable monolithic S/H's commonly exhibit more than 1 LSB equivalent error at the 12-bit level by themselves.

As a member of the A/D/A/M series of analog data acquisition modules, the A/D/A/M-822 is fully integrated and tested as a subsystem. This frees the system engineer from performing a myriad of time-consuming design tasks and minimizes system production and test efforts. With no need to design a

printed circuit layout for critical analog components, users avoid potential costly PC design iterations, which are commonly required to eliminate ground loops and other noise and error sources. A fully tested—and shielded subsystem, the A/D/A/M-822 offers superior performance, ease of use, and integration, at a lower cost than the parts alone for a comparable custom design.

TYPICAL TIMING

Figure 2 shows a typical timing relationship among the various control signals required by the A/D/A/M-822. In this example, channels 2A and 2B are selected first. Their input signals are sampled simultaneously, then the samples are sequentially converted to digital data. Subsequently, the process is repeated for channels 1A and 1B.

The S/H amplifiers require $5 \mu s$ to simultaneously acquire the signals on both input channels (to within ½ LSB for a worst case full-scale input step). Once the signal pair is acquired, the S/H Control can be switched to the HOLD mode. Because the sample-to-hold-mode settling time (input switch settling time) is less than the A/D Trigger's internal propagation delay,

the S/H Control input can be used as the A/D Trigger input, if the application warrants.

The diagram shows input switch settling time and S/H Select settling time to be 2 μs each. These are maximum times; typical values are 1 μs each. The diagram also shows that the output data from the A/D converter is valid at the instant of the EOC falling edge transition. The output data can be read at this instant or at any time up to the next A/D Trigger, since the last bit (LSB) decision is made, and the result settled, prior to the EOC transition. The S/H Control can be switched to SAMPLE while the data is being read, with no effect on the data.

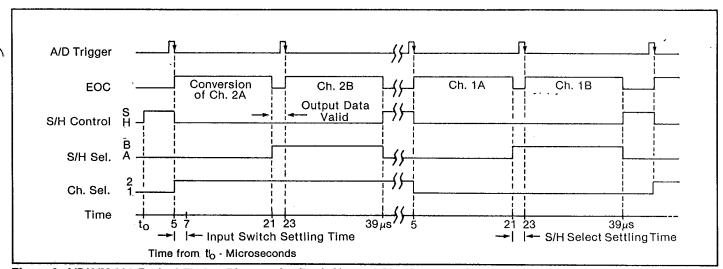


Figure 2. A/D/A/M-822 Typical Timing Diagram for Dual-Channel Simultaneous Sampling, ±10V FSR.

Unipolar Binary		Offset Binary*		Two's Complement*		
Input + 9.9976V 0.0000V	B1, B2, 111 111 11 000 000 00		Input + 9.9951V 0.0000V 10.0000V	B1, B2,, B12 111 111 111 111 100 000 000 000 000 000	Input + 9.9951V 0.0000V - 10.0000V	B1, B2,, B12 011 111 111 111 000 000 000 000 100 000 0

ADJUSTMENTS & GALIBRATION

OFFSET

A separate, external 20 kΩ multi-turn potentiometer for each S/H amplifier is recommended, per Figure 3. The +15V source used to power the A/D/A/M-822 may be used for the offset circuit as well.

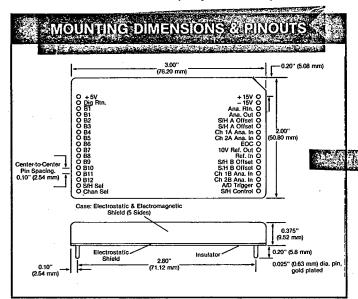
With S/H A selected and the S/H Control line at logic "1" (Sample), supply the input indicated in the Calibration Voltages table to either Ch. 1 or Ch 2. Adjust the S/H A offset pot until the LSB of the output data word varies equally between 0 and 1. Repeat the above procedure for S/H B.

GAIN

If gain trimming is required by the application, a 100Ω , multiturn potentiometer connected between the 10V Ref Out and Ref In pins per Figure 4 will provide an approximate $\pm 0.25\%$ FSR adjustment in gain. For many applications, a fixed, 50Ω 1% resistor may be used in place of the trimpot.

Gain will rarely require recalibration in most applications. If gain is to be adjusted, follow the procedure below, after performing the offset adjust procedure for both S/H's.

Select any channel by providing the appropriate logic levels to the Channel Select, S/H Select, and S/H Control lines (S/H Control should be in the SAMPLE mode—logic "1"). Supply the input indicated in the Calibration Voltages table to the selected channel. Adjust the optional 100Ω trimpot until the LSB of the data word varies equally between 0 and 1.



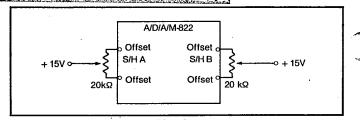


Figure 3. Offset Trimming Circuit.

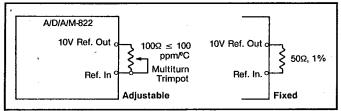


Figure 4. Gain Trimming Circuit.

Calibration Voltages						
Adjustment Procedure	Input Full Scale Range					
	0 to +10V	± 10V	±5V			
Offset	+ 0.0012V	+ 0.0024V	+ 0.0012V			
Gain	+ 9.9976V	+ 9.9951V	+ 4.9975			

and the same		en e	a destronada		
		ORDERING	a GUIDE∄		
15.23					
For	an input vol	age range of	Sin	nply Specify	7.
	0 to +10			A/D/A/M 82:	
	±10	V FSR		A/D/A/M 82	2-2
	±!	V FSR		A/D/A/M 82	2-3
				# AT "#	

ANALOGIC, **=**

ANALOGIC CORPORATION • Audubon Road • Wakefield, Massachusetts 01880 Tel. (617) 246-0300 • TWX (710) 348-0425 • Telex 94-9307
ANALOGIC INTERNATIONAL • Audubon Road • Wakefield, Massachusetts 01880 Tel. (617) 246-0300 • TWX (710) 348-0425 • Telex 94-9307
ANALOGIC GmbH • Daimlerring 2 • 6200 Wiesbaden — Nordenstadt • Germany Tel. (49) 6122-4071/74 • Telex 841-4182587
ANALOGIC LIMITED • 68 High Street • Weybridge, Surrey, KT13 8BN, England Tel. (44) 932-56011 • Telex 851-928030 ANALOGIC REGIONAL OFFICES
San Jose, California • Tel. (408) 247-6448 • Cincinnati, Ohio • Tel. (606) 371-0064

AVAILABLE FROM:

Bulletin No. 16-100227 REV 0

Printed in U.S.A.

Copyright 1982 ANALOGIC Corporation

